**Product data sheet** 

# 1. General description

WG50S65HAW1 uses advanced Fine Trench Field-stop IGBT technology with antiparallel diode in TO247 package to provide extremely low  $V_{\text{CE(sat)}}$ , and excellent switching performance. This device offers Best-in-Class efficiency in hard switching and resonant topology.



### 2. Features and benefits

- · Maximum junction temperature 175 °C
- · Positive Temperature efficient for easy paralleling
- · Very soft, fast recovery anti-parallel diode
- · High switching speed
- · EMI Improved Design

## 3. Applications

- PFC
- Solar converters
- UPS
- Welding Converters
- · Mid to high range switching frequency converters

### 4. Quick reference data

#### Table 1. Quick reference data

| Symbol               | Parameter  |  | Notes | Value |      |     | Unit |
|----------------------|--|--|-------|-------|------|-----|------|
| V <sub>CE</sub>      | Collector-emitter voltage, T <sub>j</sub> ≥ 25 °C                      |  |       | 650   |      |     | V    |
| I <sub>C</sub>       | DC collector current, limited by $T_{j(max)}$<br>$T_C = 100~^{\circ}C$ |  |       |       | 50   |     | A    |
| Symbol               | Parameter  | Conditions   | Notes | Min   | Тур  | Max | Unit |
| Static cha           | Static characteristics   |  |       |       |      |     |      |
| V <sub>CE(sat)</sub> | Collector-emitter saturation voltage                                   | $V_{GE} = 15 \text{ V}; I_{C} = 50 \text{ A}; T_{j} = 25 \text{ °C}$ |       | -     | 1.75 | 2.3 | V    |

# 5. Pinning information

## **Table 2. Pinning information**

| Pin | Symbol | Description                           | Simplified outline | Graphic symbol |
|-----|--------|---------------------------------------|--------------------|----------------|
| 1   | G      | gate                                  |                    | •C             |
| 2   | С      | collector                             |                    |                |
| 3   | E      | emitter                               |                    |                |
| mb  | С      | mounting base; connected to collector | TO247              | G E<br>sym200  |

# 6. Ordering information

### **Table 3. Ordering information**

| Type number | Package<br>Name | Orderable part number | Packing method | Small packing quantity | Package version | Package issue date |
|-------------|-----------------|-----------------------|----------------|------------------------|-----------------|--------------------|
| WG50S65HAW1 | TO247           | WG50S65HAW1Q          | Tube           | 30                     | SOT429          | 25-Mar-2013        |

# 7. Marking

#### **Table 4. Marking codes**

| Type number | Marking codes  |
|-------------|----------------|
| WG50S65HAW1 | G50S65<br>HAW1 |

# 8. Limiting values

### Table 5. Limiting values

| Symbol               | Parameter  | Notes | Value       | Unit |
|----------------------|--|-------|-------------|------|
| V <sub>CE</sub>      | Collector-emitter voltage, T <sub>j</sub> ≥ 25 °C  |       | 650         | V    |
| I <sub>c</sub>       | DC collector current, limited by $T_{j(max)}$<br>$T_{c}$ = 25 °C<br>$T_{c}$ = 100 °C                       |       | 100<br>50   | А    |
| I <sub>C(puls)</sub> | Pulsed collector current, t <sub>p</sub> limited by T <sub>j(max)</sub>                                    |       | 150         | Α    |
| -                    | Turn off safe operating area $V_{CE} \le 650 \text{ V}, T_j \le 175 ^{\circ}\text{C}, t_p = 1 \mu\text{s}$ |       | 150         | А    |
| I <sub>F</sub>       | Diode forward current, limited by $T_{j(max)}$<br>$T_{C}$ = 25 °C<br>$T_{C}$ = 100 °C                      |       | 60<br>30    | A    |
| I <sub>Fpuls</sub>   | Diode pulsed current, t <sub>p</sub> limited by T <sub>j(max)</sub>  |       | 90          | А    |
| $V_{GE}$             | Gate-emitter voltage   |       | ±20         | V    |
| P <sub>tot</sub>     | Power dissipation $T_C = 25 ^{\circ}\text{C}$<br>Power dissipation $T_C = 100 ^{\circ}\text{C}$            |       | 312<br>156  | W    |
| T <sub>stg</sub>     | Storage temperature  |       | -55 to +150 | °C   |
| T <sub>jmax</sub>    | Maximum operating junction temperature   |       | 175         | °C   |
| -                    | Peak soldering temperture  |       | 260         | °C   |
| M                    | Mounting Torque with washer  |       | 0.55        | Nm   |

### 9. Thermal characteristics

**Table 6. Thermal characteristics** 

| Symbol               | Parameter                                      | Conditions | Notes | Min | Тур  | Max | Unit |
|----------------------|--|------------|-------|-----|------|-----|------|
| R <sub>th(j-c)</sub> | IGBT thermal resistance from junction to case  |            |       | -   | 0.48 | -   | K/W  |
| R <sub>th(j-c)</sub> | Diode thermal resistance from junction to case |            |       | -   | 0.94 | -   | K/W  |
| R <sub>th(j-a)</sub> | thermal resistance from junction to ambient    |            |       | -   | 40   | -   | K/W  |

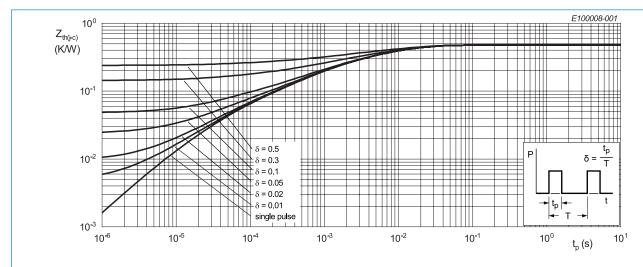


Fig. 1. Transient thermal impedance from junction to case as a function of pulse duration; IGBT

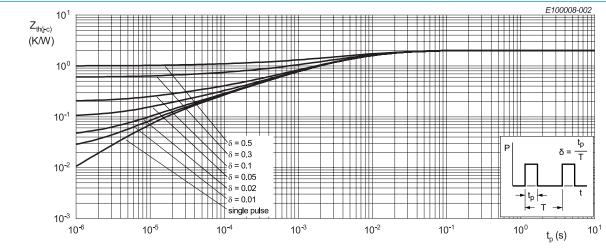


Fig. 2. Transient thermal impedance from junction to case as a function of pulse duration; Diode

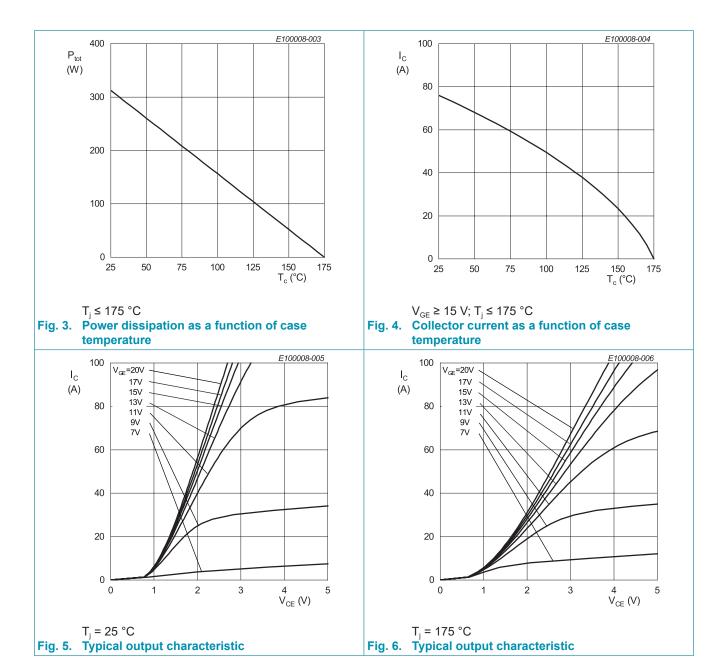
## 10. Characteristics

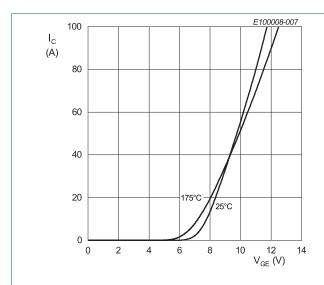
#### **Table 7. Characteristics**

| Symbol               | Parameter                           | Conditions   | Notes | Min | Тур  | Max | Unit |
|----------------------|-------------------------------------|--|-------|-----|------|-----|------|
| Static cha           | aracteristics                       |  |       |     |      |     |      |
| $BV_CES$             | Collector-emitter breakdown voltage | $V_{GE} = 0 \text{ V}; I_{C} = 1.0 \text{ mA}$                             |       | 650 | -    | -   | V    |
| $V_{\text{CE(sat)}}$ | Collector-emitter saturation        | $V_{GE} = 15 \text{ V}; I_{C} = 50 \text{ A}; T_{j} = 25 \text{ °C}$       |       | -   | 1.75 | 2.3 | V    |
|                      | voltage                             | $V_{GE}$ = 15 V; $I_{C}$ = 50 A; $T_{j}$ = 175 °C                          |       | -   | 2.35 | -   | V    |
| $V_{F}$              | Diode forward voltage               | $V_{GE} = 0 \text{ V}; I_F = 30 \text{ A}; T_j = 25 \text{ °C}$            |       | -   | 1.75 | -   | V    |
|                      |                                     | $V_{GE} = 0 \text{ V}; I_F = 30 \text{ A}; T_j = 175 ^{\circ}\text{C}$     |       | -   | 1.45 | -   | V    |
| $V_{\text{GE(th)}}$  | Gate-emitter threhold voltage       | $I_{\rm C}$ = 0.6 mA; $V_{\rm CE}$ = $V_{\rm GE}$                          |       | 3.6 | 4.5  | 5.4 | V    |
| I <sub>CES</sub>     | Zero gate voltage collector current | $V_{CE} = 650 \text{ V}; V_{GE} = 0 \text{ V}; T_j = 25 \text{ °C}$        |       | -   | -    | 100 | μA   |
|                      |                                     | $V_{CE} = 650 \text{ V}; V_{GE} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$ |       | -   | -    | 1   | mA   |
| g <sub>fs</sub>      | Transconductance                    | $V_{CE} = 20 \text{ V}; I_{C} = 50 \text{ A}$                              |       | -   | 29   | -   | S    |
| Dynamic              | characteristics                     |  |       |     |      |     |      |
| C <sub>ies</sub>     | Input capacitance                   | $V_{CE} = 30 \text{ V}; V_{GE} = 0 \text{ V}; f = 1 \text{ MHz};$          |       | -   | 1591 | -   | pF   |
| C <sub>oes</sub>     | Output capacitance                  | $T_j = 25 ^{\circ}\text{C}$  |       | -   | 58   | -   | pF   |
| C <sub>res</sub>     | Reverse transfer capacitance        |  |       | -   | 17   | -   | pF   |
| $Q_{G}$              | Gate charge                         | $V_{CC}$ = 520 V; $I_{C}$ = 50 A; $V_{GE}$ = 15 V; $T_{j}$ = 25 °C         |       | -   | 72   | -   | nC   |

# 11. Switching Characteristics

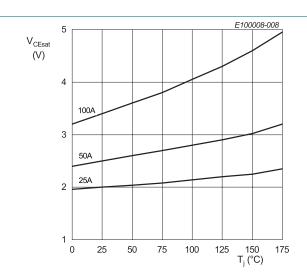
| Symbol             | Parameter                     | Conditions   | Notes | Min | Тур  | Max | Unit |
|--------------------|-------------------------------|--|-------|-----|------|-----|------|
| IGBT cha           | racteristics                  |  |       |     |      |     |      |
| $t_{d(on)}$        | Turn-on delay time            | T <sub>j</sub> = 25 °C;  |       | -   | 31   | -   | nS   |
| t <sub>r</sub>     | Rise time                     | $V_{CC} = 400 \text{ V}; I_C = 50 \text{ A}; V_{GE} = 15 \text{V} / 0 \text{V};$ $R_G = 10 \Omega$   |       | -   | 47   | -   | nS   |
| $t_{d(off)}$       | Turn-off delay time           |  |       | -   | 122  | -   | nS   |
| t <sub>f</sub>     | Fall time                     |  |       | -   | 38   | -   | nS   |
| E <sub>on</sub>    | Turn-on energy                |  |       | -   | 1.25 | -   | mJ   |
| E <sub>off</sub>   | Turn-off energy               |  |       | -   | 0.65 | -   | mJ   |
| E <sub>ts</sub>    | Total switching energy        |  |       | -   | 1.9  | -   | mJ   |
| t <sub>d(on)</sub> | Turn-on delay time            | $T_{j} = 175 ^{\circ}\text{C};$<br>$V_{CC} = 400 \text{V};  I_{C} = 50 \text{A};  V_{GE} = 15 \text{V} / 0 \text{V};$<br>$R_{G} = 10 \Omega$ |       | -   | 29   | -   | nS   |
| t <sub>r</sub>     | Rise time                     |  |       | -   | 46   | -   | nS   |
| $t_{d(off)}$       | Turn-off delay time           |  |       | -   | 139  | -   | nS   |
| t <sub>f</sub>     | Fall time                     |  |       | -   | 40   | -   | nS   |
| E <sub>on</sub>    | Turn-on energy                |  |       | -   | 1.85 | -   | mJ   |
| E <sub>off</sub>   | Turn-off energy               |  |       | -   | 0.8  | -   | mJ   |
| E <sub>ts</sub>    | Total switching energy        |  |       | -   | 2.65 | -   | mJ   |
| Diode cha          | aracteristics                 |  |       | 1   |      |     |      |
| t <sub>rr</sub>    | Reverse recovery time         | T <sub>j</sub> = 25 °C;  |       | -   | 485  | -   | nS   |
| Q <sub>r</sub>     | Reverse recovery charge       | $\dot{V}_R = 400 \text{ V}; I_F = 30 \text{ A}; dI_F/dt = 500 \text{A/us}$   |       | -   | 336  | -   | nC   |
| I <sub>RM</sub>    | Reverse recovery peak current |  |       | -   | 12.5 | -   | А    |
| t <sub>rr</sub>    | Reverse recovery time         | T <sub>j</sub> = 175 °C;<br>V <sub>R</sub> = 400 V; I <sub>F</sub> = 30 A; dI <sub>F</sub> /dt = 500A/us                                     |       | -   | 101  | -   | nS   |
| Q <sub>r</sub>     | Reverse recovery charge       |  |       | -   | 1193 | -   | nC   |
| I <sub>RM</sub>    | Reverse recovery peak current |  |       | -   | 21   | -   | А    |





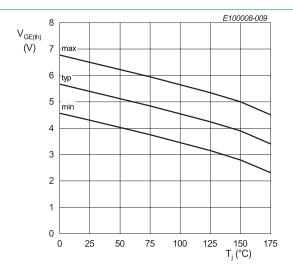
 $V_{CE} = 20 \text{ V}$ 

Fig. 7. Typical transfer characteristic



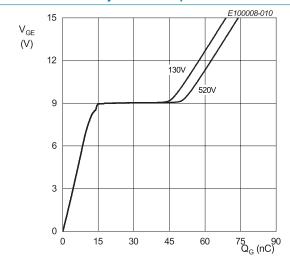
 $V_{GE} = 15 V$ 

Fig. 8. Typical collector-emitter saturation voltage as a function of junction temperature



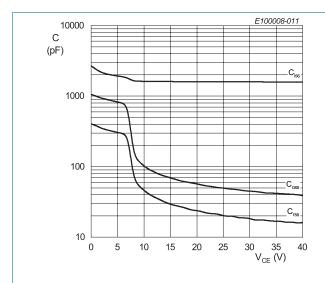
 $I_{c} = 600 \mu A$ 

Fig. 9. Gate-emitter threshold voltage as a function of junction temperature



 $I_{c} = 50 \text{ A}$ 

Fig. 10. Typical gate charge



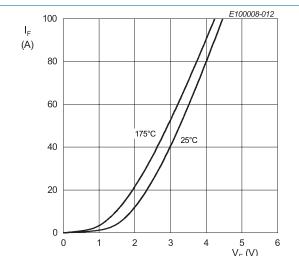
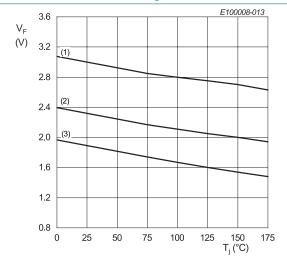
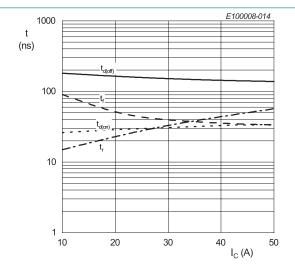


Fig. 12. Typical diode forward current as a function of forward voltage

 $\label{eq:VGE} V_{GE} = 0 \ V; \ f = 1 \ MHz$  Fig. 11. Typical capacitance as a function of collector-emitter voltage

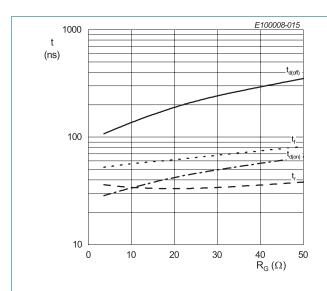




(1)  $I_F = 40 A$ (2)  $I_F = 20 A$ (3)  $I_F = 10 A$   $R_{g}$  = 10  $\Omega;$   $V_{GE}$  = 15V/0V;  $T_{j}$  = 175 °C;  $V_{CE}$  = 400 V; inductive load

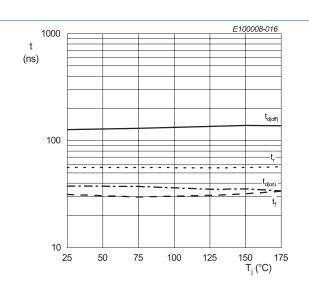
Fig. 13. Typical diode forward voltage as a function of junction temperature

Fig. 14. Typical switching times as a function of collector current



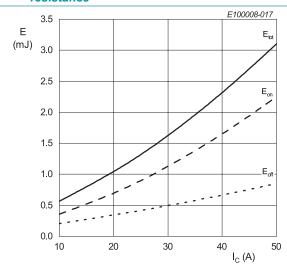
 $I_C$  = 50 A;  $V_{GE}$  = 15V/0V;  $T_j$  = 175 °C;  $V_{CE}$  = 400 V; inductive load

Fig. 15. Typical switching times as a function of gate resistance



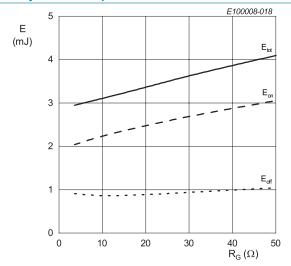
 $I_{C}$  = 50 A;  $V_{GE}$  = 15V/0V;  $R_{g}$  = 10  $\Omega$ ;  $V_{CE}$  = 400 V; inductive load

Fig. 16. Typical switching times as a function of junction temperature



 $R_g$  = 10  $\Omega$ ;  $V_{GE}$  = 15V/0V;  $T_j$  = 175 °C;  $V_{CE}$  = 400 V; inductive load

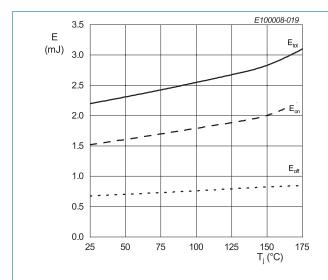
Fig. 17. Typical switching energy losses as a function of collector current

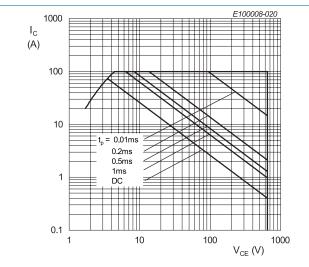


 $I_{C}$  = 50 A;  $V_{GE}$  = 15V/0V;  $T_{j}$  = 175 °C;  $V_{CE}$  = 400 V; inductive load

Fig. 18. Typical switching energy losses as a function of gate resistance

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 $I_{C}$  = 50 A;  $V_{GE}$  = 15V/0V;  $R_{g}$  = 10  $\Omega;$   $V_{CE}$  = 400 V; inductive load

Fig. 20. Forward bias safe operating area

Fig. 19. Typical switching energy losses as a function of junction temperature

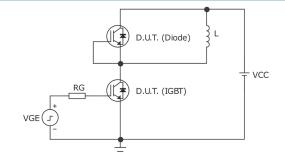


Fig. 21. Test circuit for inductive load switching

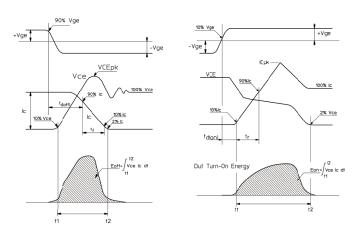
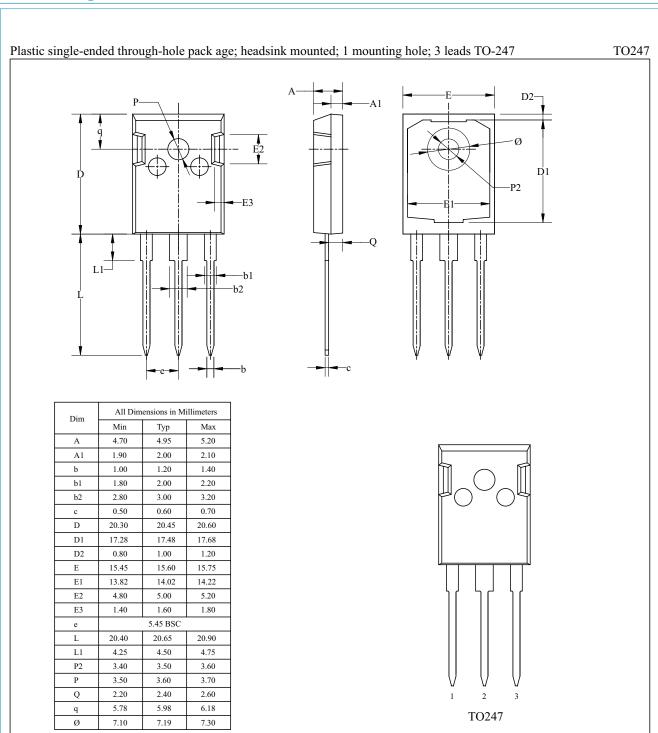


Fig. 22. Definition of switching times and losses

# 12. Package outline



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## 13. Legal information

#### Data sheet status

| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 25 November 2024

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